

# August 2007

#### FDB8453LZ

## N-Channel PowerTrench<sup>®</sup> MOSFET 40V, 50A, 7.0m $\Omega$

#### **Features**

- Max  $r_{DS(on)} = 7.0 \text{m}\Omega$  at  $V_{GS} = 10 \text{V}$ ,  $I_D = 17.6 \text{A}$
- Max  $r_{DS(on)} = 9.0 \text{m}\Omega$  at  $V_{GS} = 4.5 \text{V}$ ,  $I_D = 14.9 \text{A}$
- HBM ESD protection level of 7.6kV typical (note 4)
- Fast Switching
- RoHS Compliant

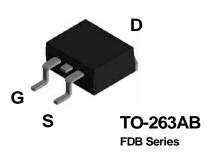


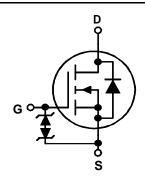
#### **General Description**

This N-Channel MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench® process that has been especially tailored to minimize the on-state resistance and switching loss. G-S zener has been added to enhance ESD voltage level.

#### **Applications**

- Inverter
- Power Supplies





#### **MOSFET Maximum Ratings** $T_C = 25$ °C unless otherwise noted

Symbol	Parameter		Ratings	Units	
$V_{DS}$	Drain to Source Voltage			40	V
$V_{GS}$	Gate to Source Voltage			±20	V
	Drain Current -Continuous (Package limited)	T <sub>C</sub> = 25°C		50	
	-Continuous (Silicon limited)	T <sub>C</sub> = 25°C		74	
'D	-Continuous	T <sub>A</sub> = 25°C	(Note 1a)	16.1	Α
	-Pulsed			100	
E <sub>AS</sub>	Single Pulse Avalanche Energy		(Note 3)	253	mJ
Б	Power Dissipation	T <sub>C</sub> = 25°C		66	14/
$P_{D}$	Power Dissipation	T <sub>A</sub> = 25°C	(Note 1a)	3.1	W
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range			-55 to +150	°C

#### **Thermal Characteristics**

$R_{\theta JC}$	Thermal Resistance, Junction to Case		1.88	°C/W
$R_{\theta,IA}$	Thermal Resistance, Junction to Ambient	(Note 1a)	40	C/VV

#### **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDB8453LZ	FDB8453LZ	TO-263AB	330mm	24mm	800 units

### **Electrical Characteristics** $T_J = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter Test Conditions		Min	Тур	Max	Units
Off Chara	acteristics					
$BV_{DSS}$	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	40			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250μA, referenced to 25°C		36		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = 32V, V_{GS} = 0V$			1	μΑ
I <sub>GSS</sub>	Gate to Source Leakage Current	$V_{GS} = \pm 20V, V_{DS} = 0V$			±10	μΑ

#### On Characteristics

$V_{GS(th)}$	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$	1.0	1.8	3.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D = 250 \mu A$ , referenced to 25°C		-6.0		mV/°C
		$V_{GS} = 10V, I_D = 17.6A$		6.3	7.0	
r <sub>DS(on)</sub> Static Drain to Source On Resistance	Static Drain to Source On Resistance	$V_{GS} = 4.5V, I_D = 14.9A$		7.3	9.0	mΩ
	$V_{GS} = 10V, I_D = 17.6A,$ $T_J = 125$ °C		9.9	11	11122	
9 <sub>FS</sub>	Forward Transconductance	$V_{DS} = 5V, I_{D} = 17.6A$		84		S

#### **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	$V_{DS} = 20V, V_{GS} = 0V,$ $f = 1MHz$	2665	3545	pF
C <sub>oss</sub>	Output Capacitance		325	430	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 - 1101112	200	295	pF
$R_g$	Gate Resistance	f = 1MHz	2.2		Ω

#### **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time	.,	$V_{DD} = 20V, I_D = 17.6A,$ $V_{GS} = 10V, R_{GEN} = 6\Omega$		11	20	ns
t <sub>r</sub>	Rise Time	$V_{DD} = 20V, I_D = 17$			6	13	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	v <sub>GS</sub> = 10v, K <sub>GEN</sub>			37	60	ns
t <sub>f</sub>	Fall Time				5	11	ns
$Q_g$	Total Gate Charge	V <sub>GS</sub> = 0V to 10V			47	66	nC
$Q_g$	Total Gate Charge	$V_{GS} = 0V \text{ to } 5V$	$V_{DD} = 20V,$ $I_{D} = 17.6A$		25	35	nC
$Q_{gs}$	Gate to Source Charge		1D = 17.0A		7		nC
$Q_{gd}$	Gate to Drain "Miller" Charge				9		nC

#### **Drain-Source Diode Characteristics**

1Vob Source to Drain Diode Forward Voltage F	Source to Drain Diode Forward Voltage	$V_{GS} = 0V, I_S = 2.6A$ (Note 2)	0.7	7 1.2	V
	$V_{GS} = 0V, I_{S} = 17.6A$ (Note 2)	0.0	3 1.3	•	
t <sub>rr</sub>	Reverse Recovery Time	I <sub>E</sub> = 17.6A, di/dt = 100A/μs	24	. 38	ns
Q <sub>rr</sub>	Reverse Recovery Charge	$I_{\rm F} = 17.6$ A, $I_{\rm F} = 100$ A/ $I_{\rm F} = 17.6$ A, $I_{\rm F} = 100$ A/ $I_{\rm F} = 17.6$ A, $I_{\rm F} = 17.6$	15	27	nC

R<sub>0,IC</sub> is guaranteed by design while R<sub>0,IA</sub> is determined by the user's board design.

a. 40°C/W when mounted on a 1 in² pad of 2 oz copper

b. 62.5°C/W when mounted on a minimum pad.

Pulse Test: Pulse Width < 300µs, Duty cycle < 2.0%.</li>
 Starting T<sub>J</sub> = 25°C, L = 3mH, I<sub>AS</sub> = 13A, V<sub>DD</sub> = 40V, V<sub>GS</sub> = 10V.
 The diode connected between the gate and source serves only as protection against ESD. No gate overvoltage rating is implied.

#### Typical Characteristics T<sub>J</sub> = 25°C unless otherwise noted

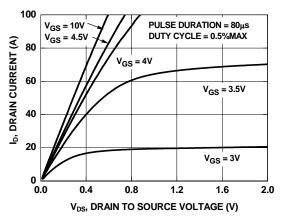


Figure 1. On-Region Characteristics

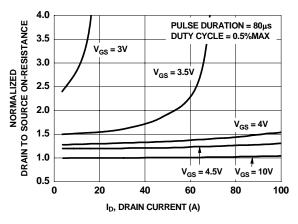


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

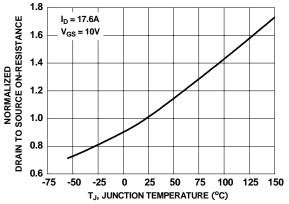


Figure 3. Normalized On-Resistance vs Junction Temperature

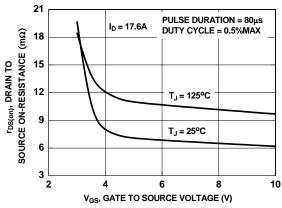


Figure 4. On-Resistance vs Gate to Source Voltage

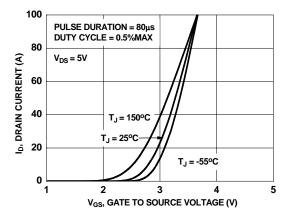


Figure 5. Transfer Characteristics

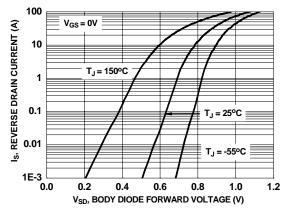


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

#### Typical Characteristics T<sub>J</sub> = 25°C unless otherwise noted

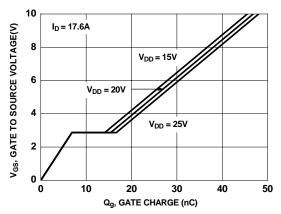


Figure 7. Gate Charge Characteristics

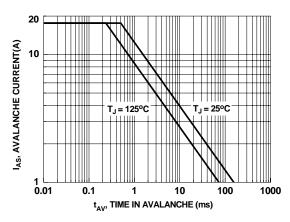


Figure 9. Unclamped Inductive Switching Capability

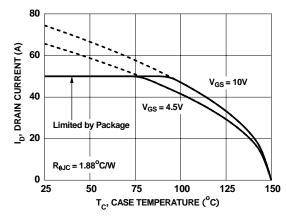


Figure 11. Maximum Continuous Drain Current vs Ambient Temperature

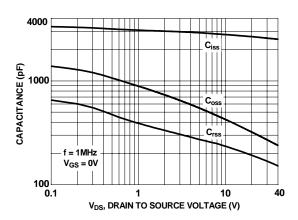


Figure 8. Capacitance vs Drain to Source Voltage

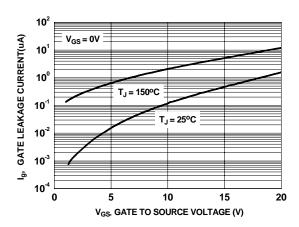


Figure 10. Gate Leakage Current vs Gate to Source Voltage

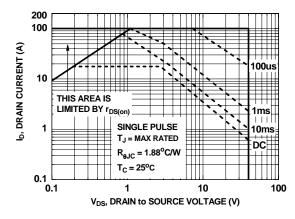


Figure 12. Forward Bias Safe Operating Area

#### Typical Characteristics T<sub>J</sub> = 25°C unless otherwise noted

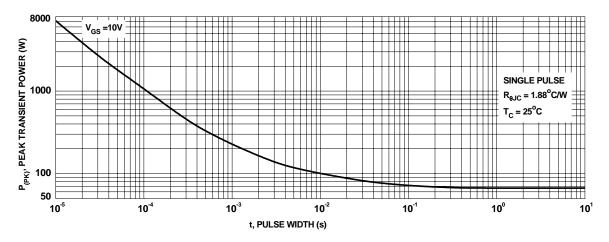


Figure 13. Single Pulse Maximum Power Dissipation

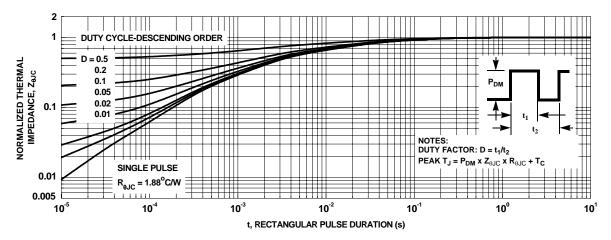


Figure 14. Transient Thermal Response Curve





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